

# Search Notes



Application/Control No.

10/071,174

Examiner

Jon Eric Angell

Applicant(s)/Patent under Reexamination

REED ET AL.

Art Unit

1635

## SEARCHED

Class	Subclass	Date	Examiner
536	23.1, 24.33	6/8/2005	JEA
536	24.3+	6/8/2005	JEA
435	320.1 325	6/8/2005	JEA
435	252.3	6/8/2005	JEA
Updated		3-2-2006	JEA
Updated		11-24-06	JEA

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
STN EAST Inventor Name searched STIC SEQ search: SEQs 1, 2, 37 including alignment of 1 and 37 Reviewed and Updated	6/8/2005	JEA
Updated	3-2-2006	JEA
Updated	11-24-06	JEA